



4/17/2012

**RELIABILITY MONITOR REPORT
FOR**

San Antonio 0.8 μ m Silicon Gate CMOS (EC8)

MAXIM Integrated Products

**120 San Gabriel Dr.
Sunnyvale, CA 94086**

**This Report was prepared by
Maxim Reliability Engineering**

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

DS75

The calculated failure rate for devices using this process is:

FAILURE RATE: MTTF (YRS): 9400 QUANTITY: 80 FAILS: 0 FITS: 12.1

The parameters used to calculate this failure rate are as follows:

Cf: 60% Ea: 0.7 Tu: 25 °C

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between 4/1/2011 and 3/31/2012 .

Process Information:

Process Description: San Antonio 0.8µm Silicon Gate CMOS (EC8)

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	1138	DS75	125C, 5.5 VOLTS	1000 HRS	80	0	FD272216AE
Total:						0	

STORAGE LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
STORAGE LIFE	1138	DS75	150C	1000 HRS	79	0	FD272216AE
Total:						0	

TEMPERATURE CYCLE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
TEMP CYCLE, 5' RAMP, 10' DWELL	1138	DS75	-55C TO 125C	1000 CYS	80	0	FD272216AE
Total:						0	

TEMPERATURE HUMIDITY BIAS

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HAST	1138	DS75	130C, 85%R.H.,5.5V	96 HRS	80	0	FD272216AE
Total:						0	

FAILURE RATE: MTTF (YRS): 9400 QUANTITY: 80 FAILS: 0 FITS: 12.1